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Application/Control No.	Applicant(s)/Patent under Reexamination	
10/067,098	AMIDAN ET AL.	
Examiner	Art Unit	
Thai D. Hoang	2616	

			
SEARCHED			
Class	Subclass	Date	Examiner
370	468-474	11/20/2006	тн
	395.665	11/20/2006	TH
370	535-544	11/20/2006	TH

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner

SEARCH NOTES (INCLUDING SEARCH STRATEGY)			
	DATE	EXMR	
EAST:Class search combines with text search, see search history printout.	11/20/2006	тн	
EAST: interference search: text search PG-PUB data base, see search history printout.	11/20/2006	тн	
NPL: IEEE, GOOGLE, IETF.	11/20/2006	тн	
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